

## CHT-NMOS80XX DATASHEET

Version: 2.4  
25-Feb-11  
(Last Modification Date)

## High-Temperature, 80V Power NMOSFET

### General description

The CHT-NMOS80XX is a high voltage N-channel mid-power MOSFET family designed to achieve high performance in an extremely wide temperature range. Typical operation temperatures go from -55°C to 225°C.

CHT-NMOS80XX parts sustain the highest temperatures while keeping leakage current low.

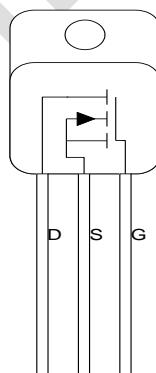
### Typical Markets

- Well logging,
- Oil & Gas,
- Aeronautics & aerospace,
- Automotive.

### Features

- Specified from -55 to +225°C (T<sub>j</sub>)
- Drain voltage up to 80V
- Typical output current (@ 25°C)
  - CHT-NMOS-8005: 7.5A
  - CHT-NMOS-8010: 13.5A
- R<sub>DSON</sub>
  - CHT-NMOS-8005: 0.99Ω @ 225°C
  - CHT-NMOS-8010: 0.44Ω @ 225°C
- V<sub>GS</sub> = 0V to +5V
- Reverse ESD diode between gate and source.
- Available in TO254 package.

### Package configurations<sup>1</sup>



TO254 (Top view) (case floating)

<sup>1</sup> Other packages available upon request.

### Ordering Information

Ordering Reference	Package	Temperature Range	Marking
CHT-NMOS8005-TO254-T	TO-254 metal can	-55°C to +225°C	CHT-NMOS8005
CHT-NMOS8010-TO254-T	TO-254 metal can	-55°C to +225°C	CHT-NMOS8010

Product Status: under qualification, preliminary datasheet

**Absolute Maximum Ratings**

Gate-to-Source voltage $V_{GS}$	-0.5V to 5.5V
Pulsed drain current $I_{DS}$ ( $T_{pulse} = 1\mu s$ )	
CHT-NMOS8005:	8.5A @ $T_j = -55^\circ C$
	7.5A @ $T_j = 25^\circ C$
	5A @ $T_j = 225^\circ C$
CHT-NMOS8010:	16A @ $T_j = -55^\circ C$
	13.5A @ $T_j = 25^\circ C$
	9A @ $T_j = 225^\circ C$
Power dissipation (with heat sink) $T_c = 25^\circ C$	
CHT-NMOS8005:	45W
CHT-NMOS8010:	45W
Junction temperature $T_j$	300°C

**Operating Conditions**

Gate-to-Source voltage $V_{GS}$	0V to 5V
Drain-to-Source voltage $V_{DS}$	0V to 80V
Power dissipation $T_c = 25^\circ C$	40W
Junction temperature	-55°C to +225°C

**ESD Rating (expected)**

Human Body Model (expected) 2kV

*Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Frequent or extended exposure to absolute maximum rating conditions or above may affect device reliability.*

Preliminary

**Electrical characteristics of CHT-NMOS8005****DC Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Threshold voltage	$V_{TH}$	$V_{DS} = 50\text{mV}$	<b>1</b>	1.6	<b>1.9</b>	V
Drain cut-off current	$I_{DSS}$	$V_{GS} = 0\text{V}, V_{DS} = 80\text{V}, T_j = 25^\circ\text{C}$		1.3		nA
		$V_{GS} = 0\text{V}, V_{DS} = 80\text{V}, T_j = 225^\circ\text{C}$		15.2		uA
Gate leakage current <sup>1</sup>	$I_{GSS}$	$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 25^\circ\text{C}$		19		nA
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 225^\circ\text{C}$		0.16		uA
Static drain-to-source resistance	$R_{DSon}$	$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = -55^\circ\text{C}$		0.37		$\Omega$
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 25^\circ\text{C}$		0.48		$\Omega$
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 225^\circ\text{C}$		0.99		$\Omega$
Breakdown drain-to-source voltage <sup>2</sup>	$V_{BRDS}$	$V_{GS} = 0\text{V}$	<b>80</b>			V

**Dynamic Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Input capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		410		pF
Output capacitance	$C_{OSS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		103		pF
Feedback capacitance	$C_{RSS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		22		pF

**Switching Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Turn-on delay time	$t_{d(ON)}$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		30		ns
Rise time	$t_r$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		52		ns
Turn-off delay time	$t_{d(OFF)}$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		60		ns
Fall time	$t_f$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		74		ns
Drain current	$I_D$	$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = -55^\circ\text{C}$		8.5		A
		$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = 25^\circ\text{C}$		7.5		A
		$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = 225^\circ\text{C}$		5		A

**Thermal Characteristics**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Junction to case thermal resistance	$\Theta_{JC}$	TO-254 package		5		$^\circ\text{C/W}$

<sup>1</sup> Includes ESD diode leakage current.

<sup>2</sup> Voltage for which the cut-off current evolution versus  $V_{DS}$  becomes exponential.

**Electrical characteristics of CHT-NMOS8010****DC Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Threshold voltage	$V_{TH}$	$V_{DS} = 50\text{mV}$	<b>1</b>	1.6	<b>1.9</b>	V
Drain cut-off current	$I_{DSS}$	$V_{GS} = 0\text{V}, V_{DS} = 80\text{V}, T_j = 25^\circ\text{C}$		12		nA
		$V_{GS} = 0\text{V}, V_{DS} = 80\text{V}, T_j = 225^\circ\text{C}$		51		uA
Gate leakage current <sup>3</sup>	$I_{GSS}$	$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 25^\circ\text{C}$		100		pA
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 225^\circ\text{C}$		390		nA
Static drain-to-source resistance	$R_{DSon}$	$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = -55^\circ\text{C}$		0.18		$\Omega$
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 25^\circ\text{C}$		0.24		$\Omega$
		$V_{GS} = 5\text{V}, V_{DS} = 50\text{mV}, T_j = 225^\circ\text{C}$		0.46		$\Omega$
Breakdown drain-to-source voltage <sup>4</sup>	$V_{BRDS}$	$V_{GS} = 0\text{V}$	<b>80</b>			V

**Dynamic Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Input capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		850		pF
Output capacitance	$C_{OSS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		205		pF
Feedback capacitance	$C_{RSS}$	$V_{GS} = 0\text{V}_{DC}, V_{DS} = 25\text{V}_{DC}$		45		pF

**Switching Characteristics**

Unless otherwise stated,  $T_j = 25^\circ\text{C}$ . **Bold** figures point out values valid over the whole temperature range ( $T_j = -55^\circ\text{C}$  to  $+225^\circ\text{C}$ ).

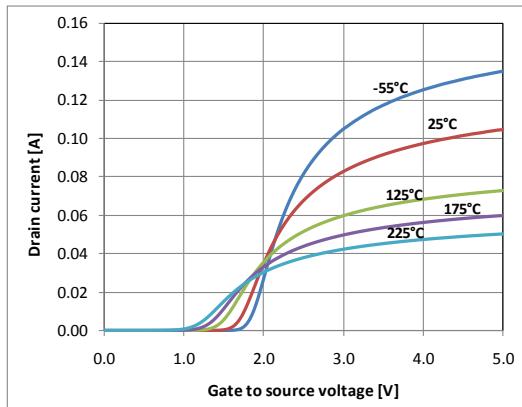
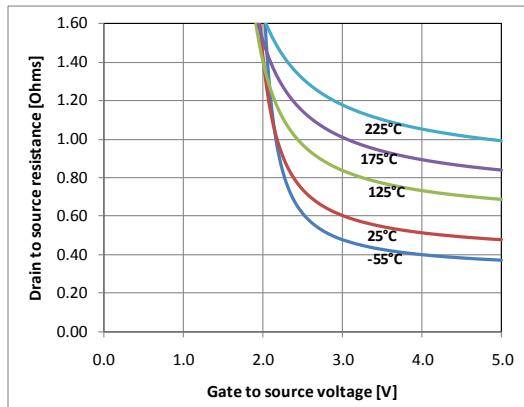
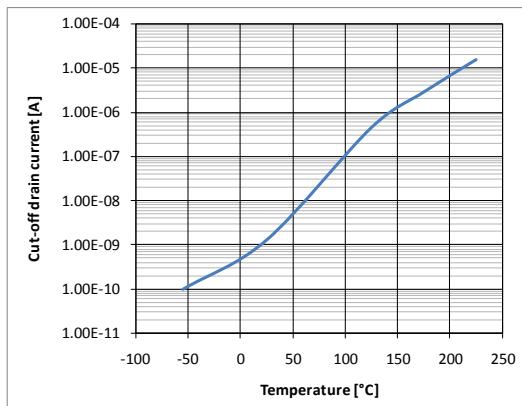
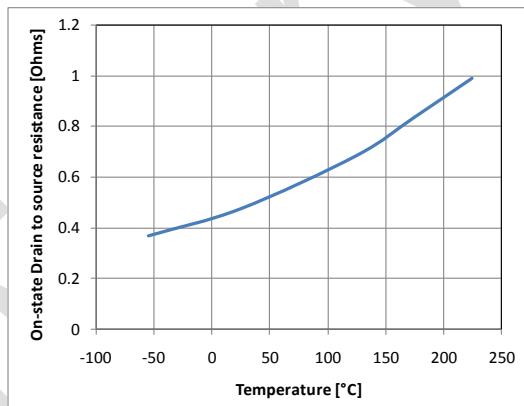
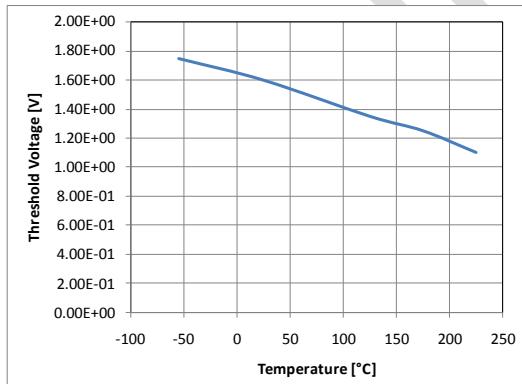
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Turn-on delay time	$t_{d(ON)}$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		<b>38</b>		ns
Rise time	$t_r$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		<b>72</b>		ns
Turn-off delay time	$t_{d(OFF)}$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		<b>102</b>		ns
Fall time	$t_f$	$V_{DS} = 40\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}$		<b>79</b>		ns
Drain current	$I_D$	$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = -55^\circ\text{C}$		16		A
		$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = 25^\circ\text{C}$		13.5		A
		$V_{DS} = 80\text{V}, V_{GS} = 5\text{V } 1\mu\text{s pulse}, T_j = 225^\circ\text{C}$		9		A

**Thermal Characteristics**

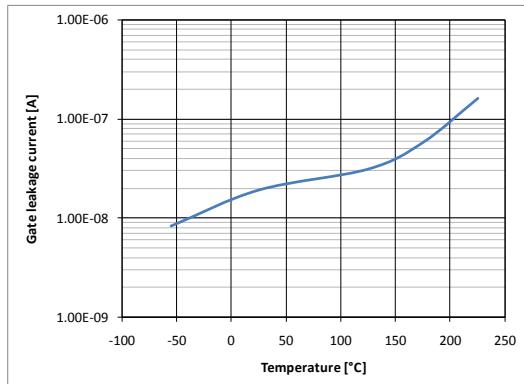
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Junction to case thermal resistance	$\Theta_{JC}$	TO-254 package		5		$^\circ\text{C/W}$

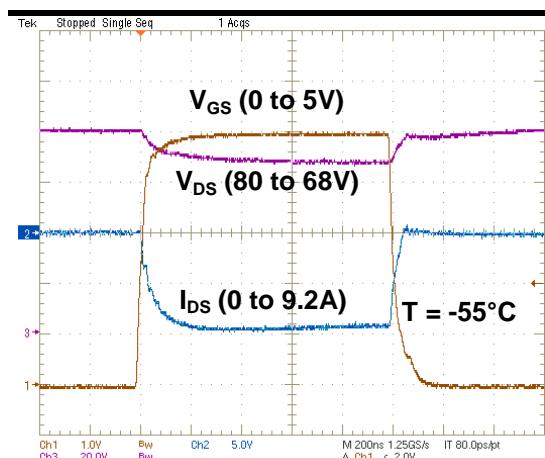
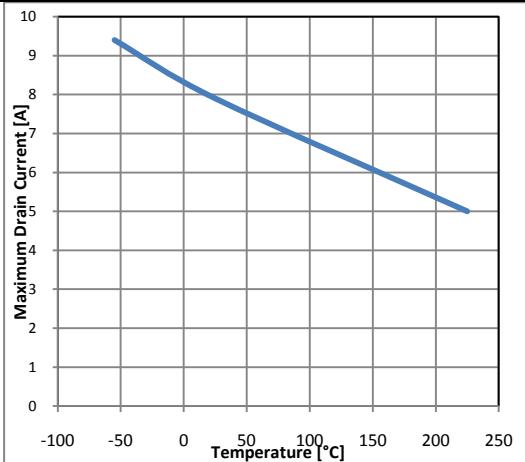
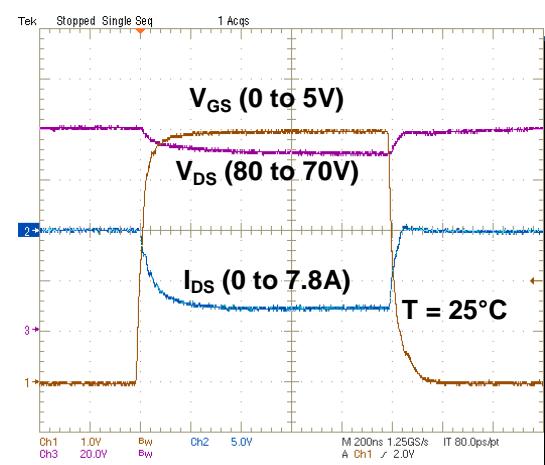
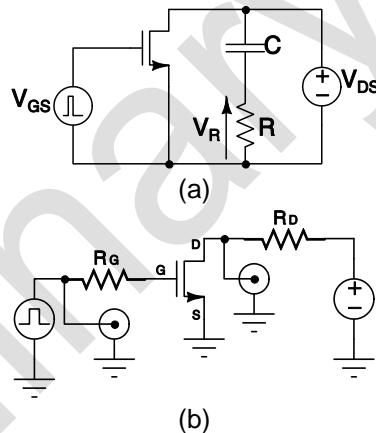
<sup>3</sup> Includes ESD diode leakage current.

<sup>4</sup> Voltage for which the cut-off current evolution versus  $V_{DS}$  becomes exponential.

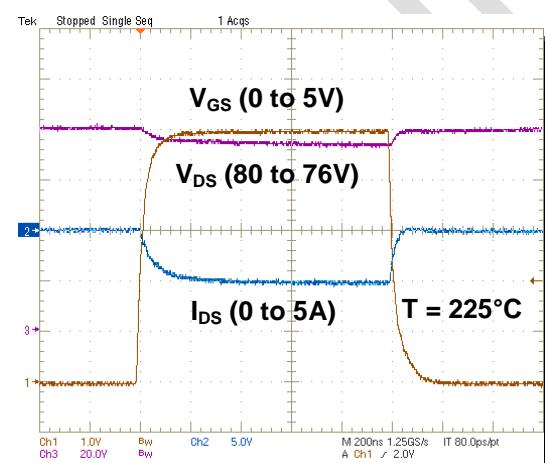
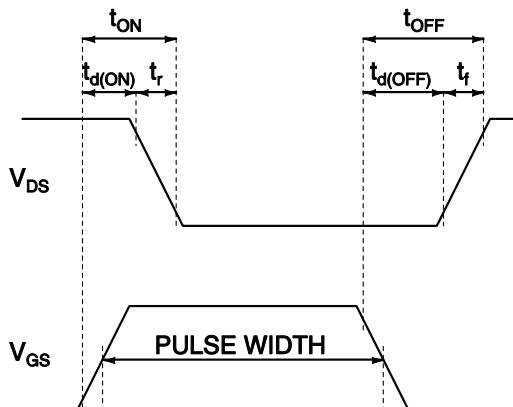
**Typical Performance Characteristics of CHT-NMOS8005**Drain current vs. gate voltage ( $V_D = 50\text{mV}$ ).Drain-source resistance vs. gate voltage( $V_D=50\text{mV}$ ).Cut-off current vs. junction temperature ( $V_G=0\text{V}$ ,  $V_D=80\text{V}$ ).On-state drain source resistance vs. junction temperature ( $V_G=5\text{V}$ ,  $V_D=50\text{mV}$ ).

Threshold voltage vs. junction temperature.

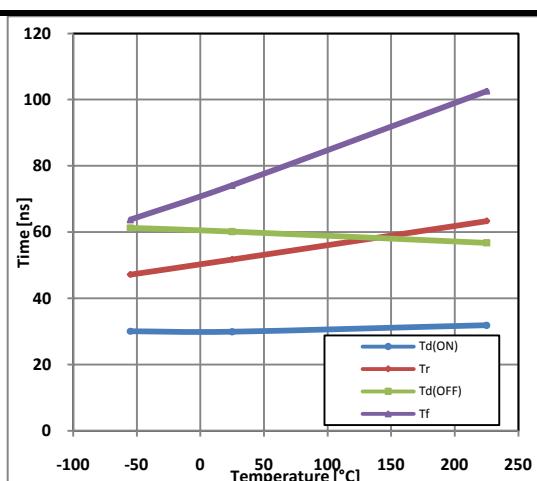
Gate and ESD diode leakage current vs. junction temperature ( $V_G=5\text{V}$ ,  $V_D=50\text{mV}$ ).

Maximum drain current pulse test ( $T_j = -55^\circ\text{C}$ ).Peak drain current vs. temperature ( $V_g=5\text{V}$ ,  $V_d=80\text{V}$ ).Maximum drain current pulse test ( $T_j = 25^\circ\text{C}$ ).

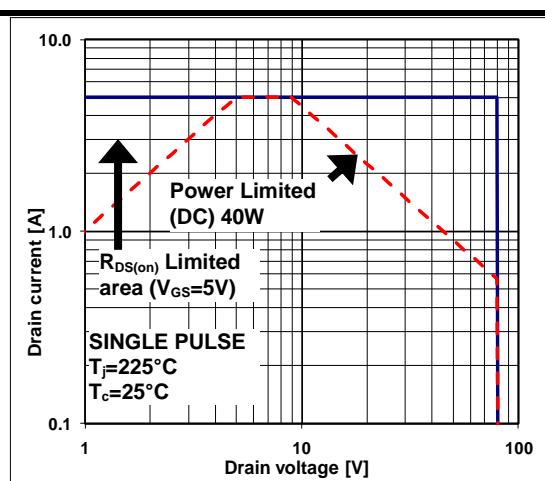
(a)  $I_D^{\text{MAX}}$  measurement scheme  $R=1\Omega$ ,  $C=100\mu\text{F}$ , Compliance ( $V_{DS}=80\text{V}$ )= $100\text{mA}$  (b) Timing measurement scheme  $R_G=0\Omega$ ,  $R_D=15\Omega$ ,  $V_{DS}=40\text{V}$ .

Maximum drain current pulse test ( $T_j = 225^\circ\text{C}$ ).

Timing definition diagram.

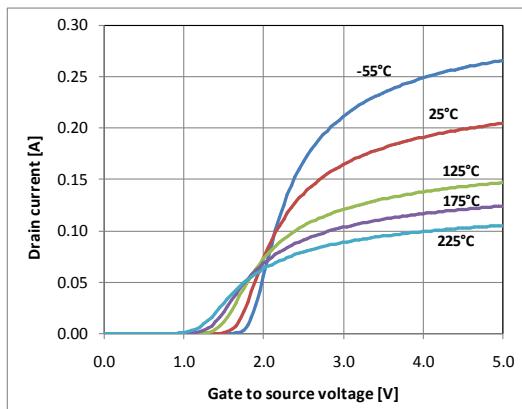
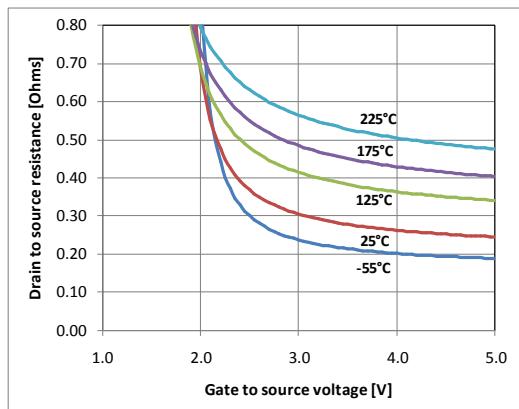
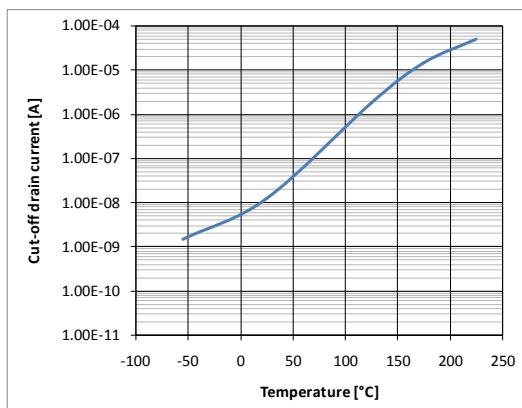
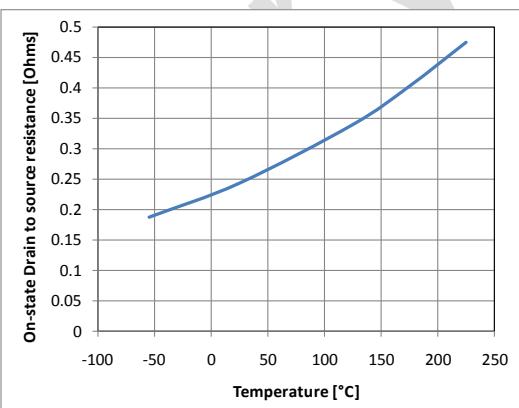
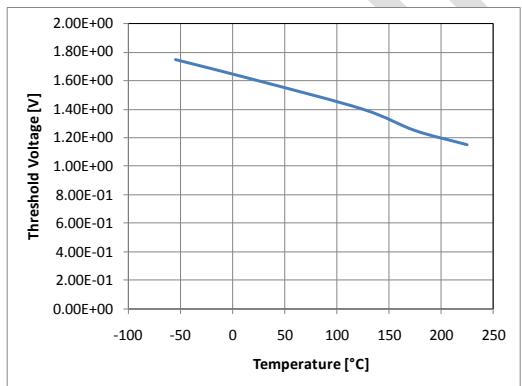


Timing parameters versus temperature.

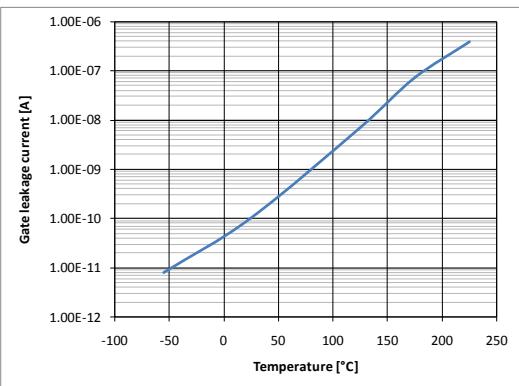


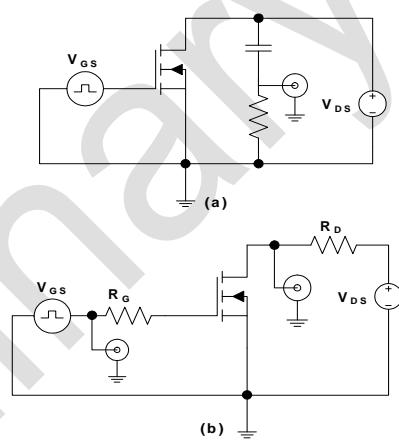
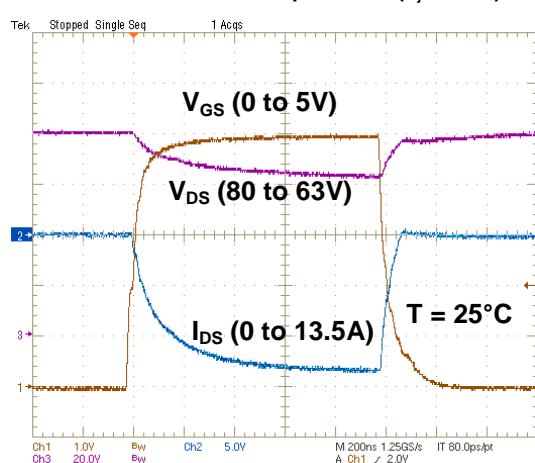
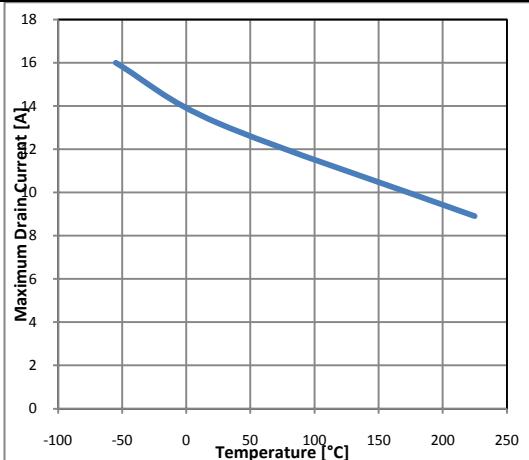
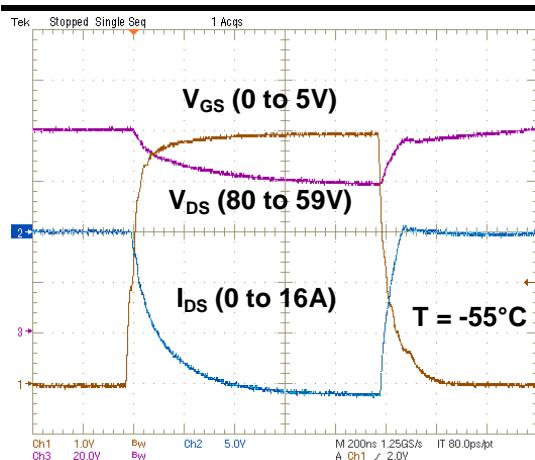
Forward bias safe operating area.

Preliminary

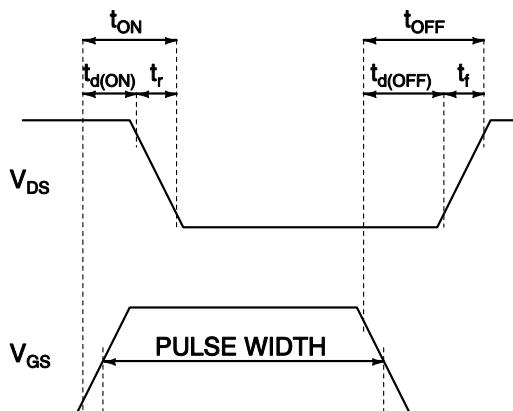
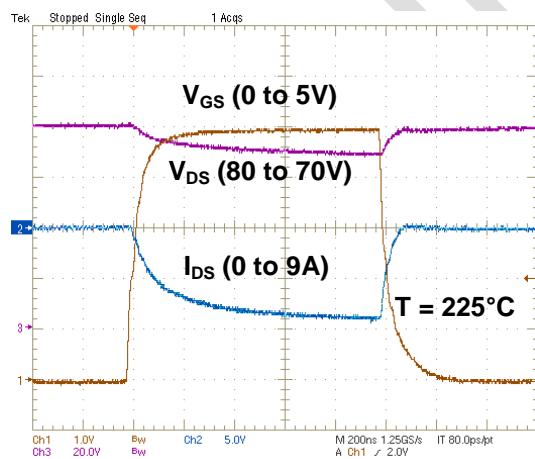
**Typical Performance Characteristics of CHT-NMOS8010**Drain current vs. gate voltage ( $V_D = 50\text{mV}$ ).Drain-source resistance vs. gate voltage ( $V_D=50\text{mV}$ ).Cut-off current vs. junction temperature ( $V_G=0\text{V}$ ,  $V_D=80\text{V}$ ).On-state drain source resistance vs. junction temperature ( $V_G=5\text{V}$ ,  $V_D=50\text{mV}$ ).

Threshold voltage vs. junction temperature.

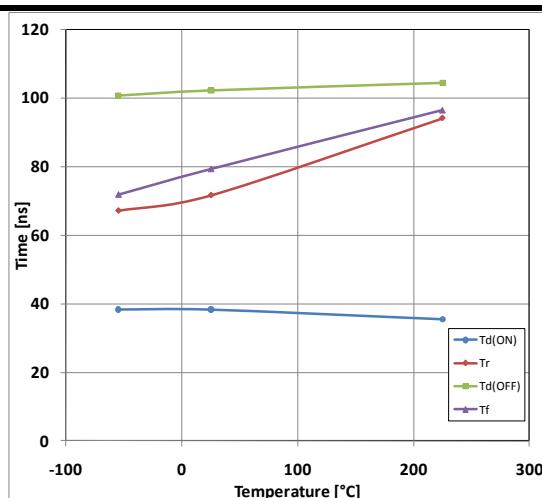
Gate and ESD diode leakage current vs. junction temperature ( $V_G=5\text{V}$ ,  $V_D=50\text{mV}$ ).



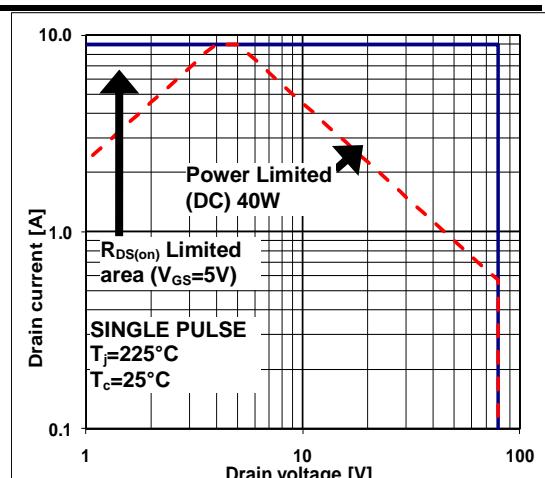
(a)  $I_{D\text{ MAX}}$  measurement scheme  $R=1\Omega$ ,  $C=100\mu\text{F}$ , Compliance ( $V_{DS}=80\text{V}$ )= $100\text{mA}$  (b) Timing measurement scheme  $R_G=0\Omega$ ,  $R_D=15\Omega$ ,  $V_{DS}=40\text{V}$ .



Timing definition diagram.



Timing parameters versus temperature.

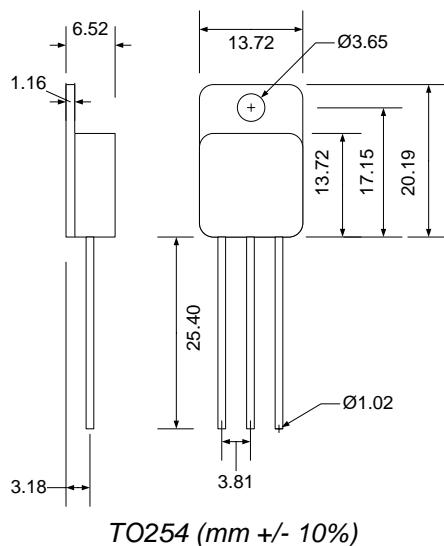


Forward bias safe operating area.

Preliminary

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## Package Dimensions



TO254 (mm +/- 10%)

## Contact & Ordering

CISSOID S.A.

Headquarters and contact EMEA:	CISSOID S.A. – Rue Francqui, 3 – 1435 Mont Saint Guibert - Belgium T : +32 10 48 92 10 - F: +32 10 88 98 75 Email: <a href="mailto:sales@cissoid.com">sales@cissoid.com</a>
Sales Representatives:	Visit our website: <a href="http://www.cissoid.com">http://www.cissoid.com</a>

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